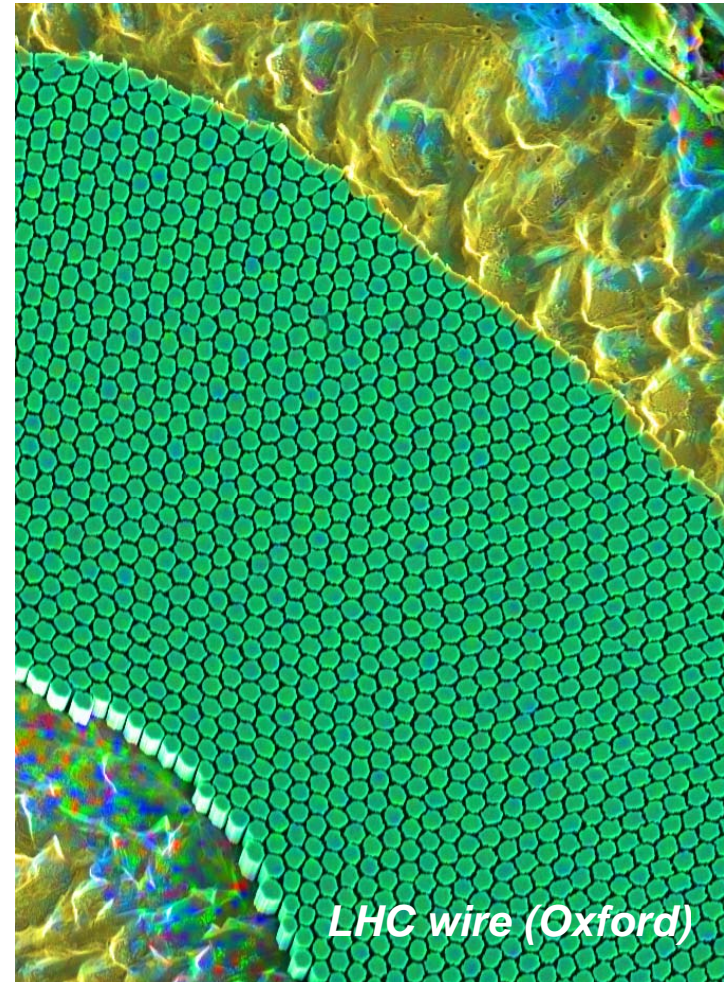


Advances in low loss NbTi Strand and Cable

Martin Wilson

Plan

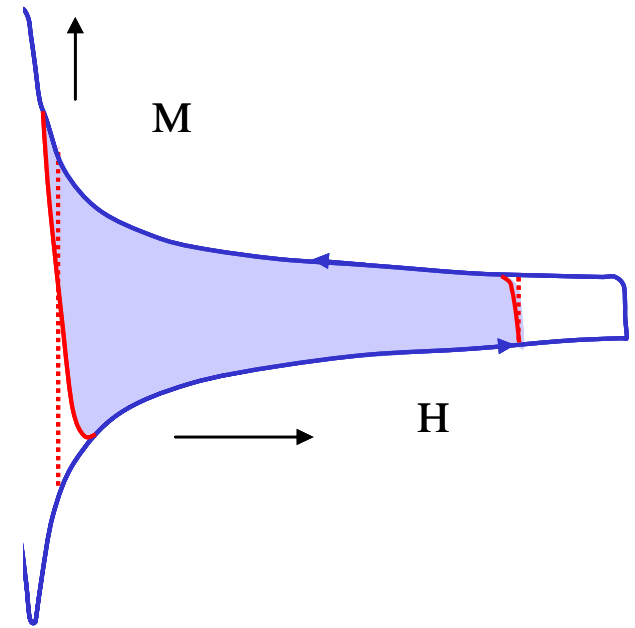
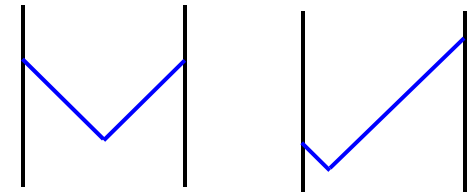
- Recapitulate general loss mechanisms
- Hysteresis loss - fine filaments
proximity coupling etc
- Coupling loss within wires - transverse
resistivity, barriers, stability
- Coupling loss between cables -
interface resistance, stability, cores



AC loss general

- work done to change the field energy $\delta E = H \delta B$
- around a closed loop, energy dissipated in a magnetic material $E = \oint \mu_o H dM = \oint \mu_o M dH$
- away from end points, loss power $P = M \dot{B}$
- superconductor magnetization comes from
 - supercurrents \Rightarrow hysteresis
 - combined supercurrents and resistive currents \Rightarrow coupling
 - classical eddy currents
- with a transport current flowing, the power supply also does work, increasing the loss by a factor

$$1 + \left(\frac{I_t}{I_c} \right)^2$$



Hysteresis

- for round filaments

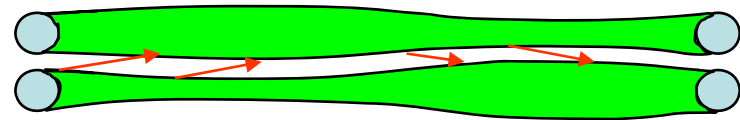
$$M = \frac{2}{3\pi} J_c d_f \quad P = \dot{B} \frac{2}{3\pi} J_c d_f$$

\Rightarrow fine filaments

Making fine filaments: resistive transition

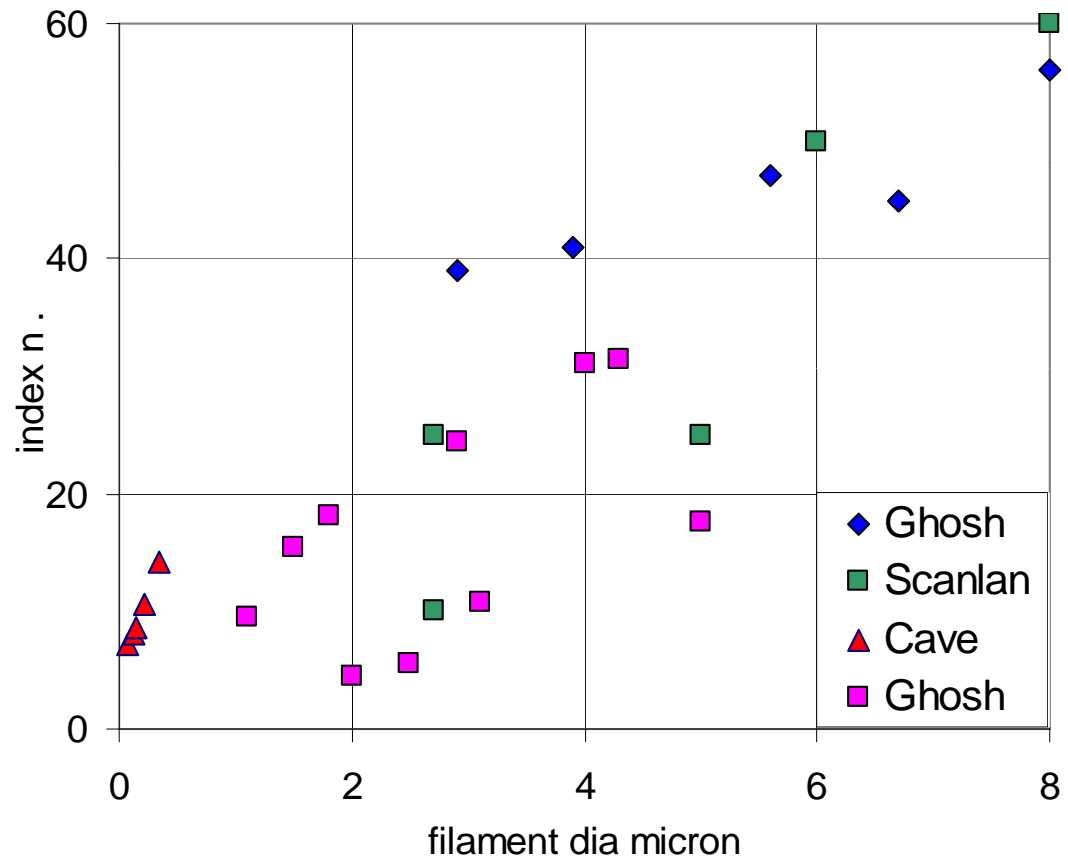
- resistive transition
- $$\rho(J) = \rho_o \left\{ \frac{J}{J_o} \right\}^n$$

- depends on processing - 'sausaging'
- n always gets worse with finer filaments, so useful J gets less
- but intrinsic J_c does not get worse



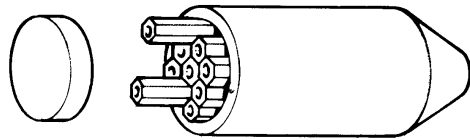
Intermetallics

- CuTi intermetallic particles formed during extrusion pre-heat
- they don't draw down with the filaments \Rightarrow breakage
- must surround filament with diffusion barrier - usually Nb

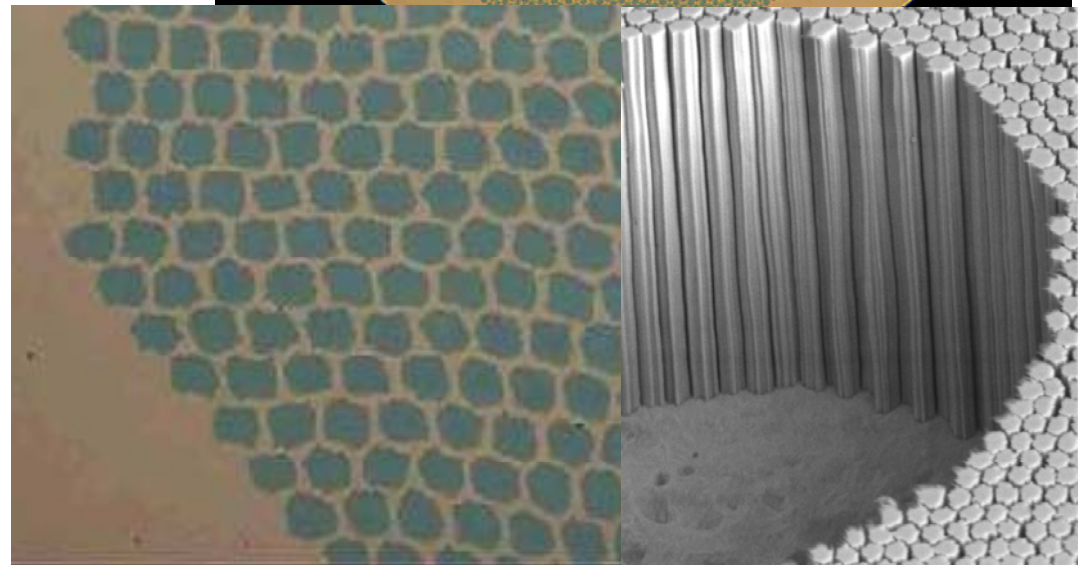
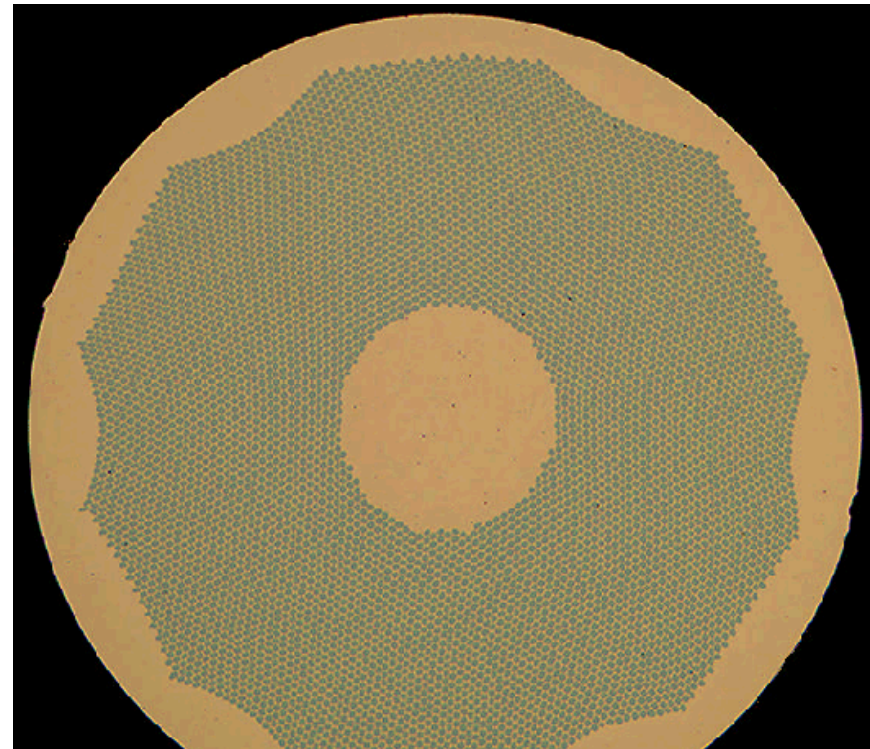


Making fine filaments: Single stacking

- single stacking makes the best wire
- when packing the extrusion cannister, rods buckle below $\sim 1.5\text{mm}$ diameter
 \Rightarrow filament crossover \Rightarrow breakage
- for a 250mm diameter extrusion cannister, this limits the number of filaments to $\sim 15,000$



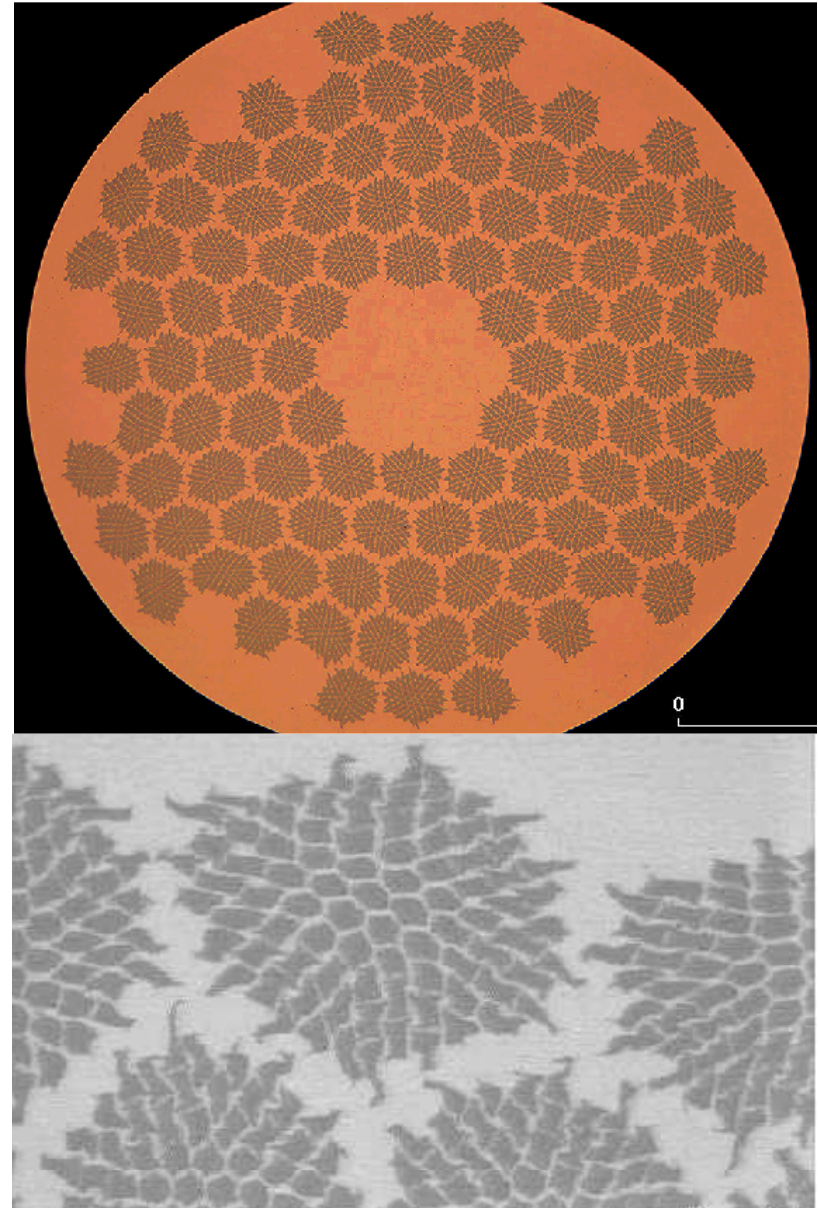
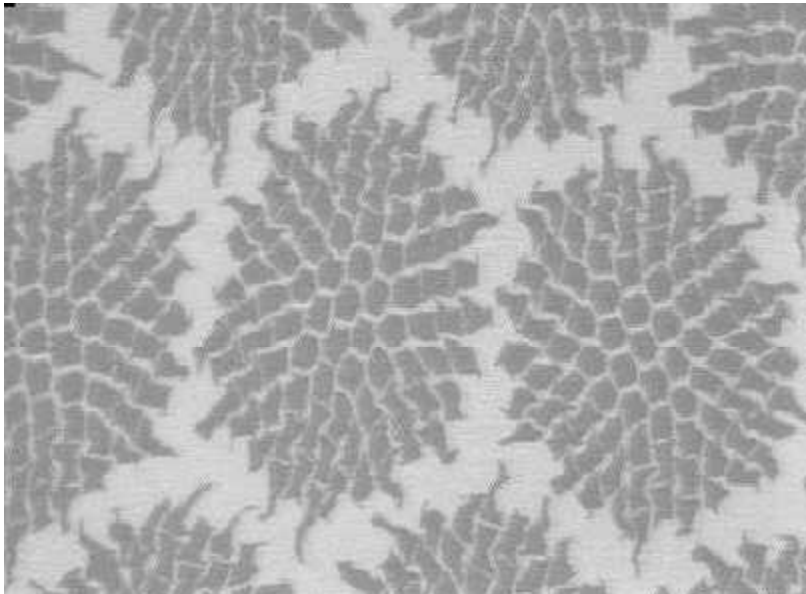
- for a 0.85mm diameter wire, 15,000 filaments
 \Rightarrow diameter $\sim 4.5\mu\text{m}$



wire 3N7 by European Advanced Superconductors

Making fine filaments: Double stacking

- double stacking is easier and allows a large number of filaments
- but the filaments are more distorted



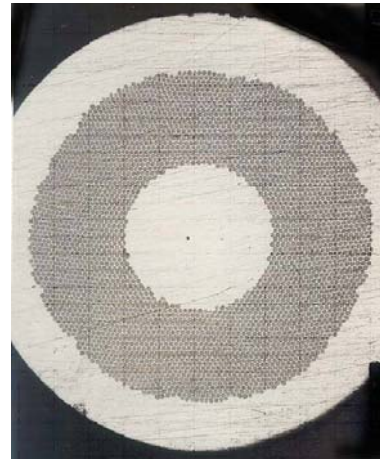
wire 2A212 by European Advanced Superconductors

Fine filaments: distortion

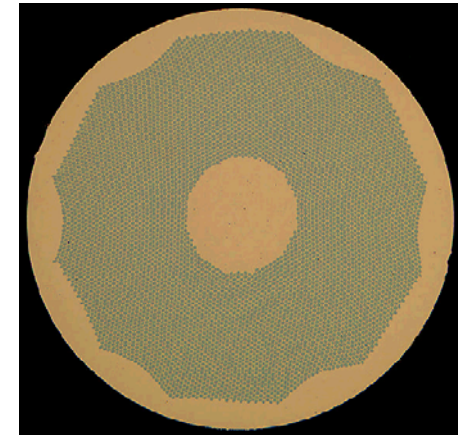
- measure magnetization extrapolated to zero B' and J_c via transport current (measure at high field to minimize self field)

- calculate ratio

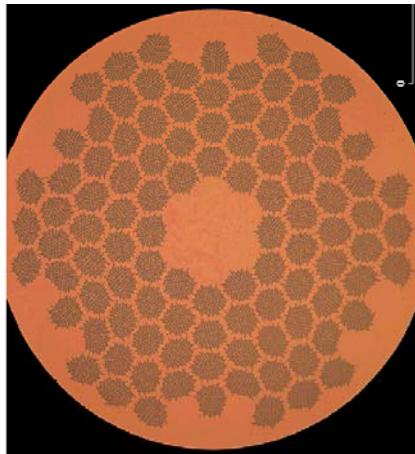
$$r = \frac{J_{cmag}}{J_{ct}}$$



Oxford RHIC: $r = 0.92$



EAS 3N7: $r = 0.94$



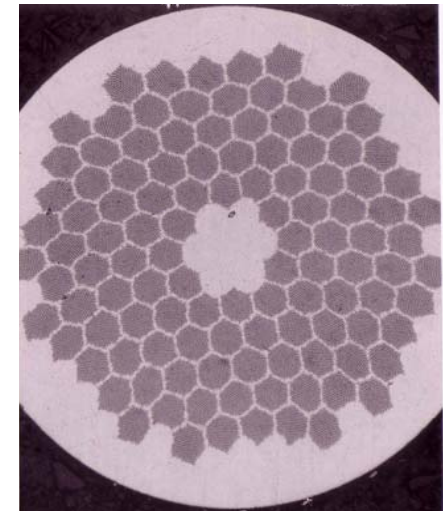
EAS 2A212:
 $r = 1.40$



EAS K2001T4:
 $r = 1.15$



EAS G2001T6:
 $r = 1.10$

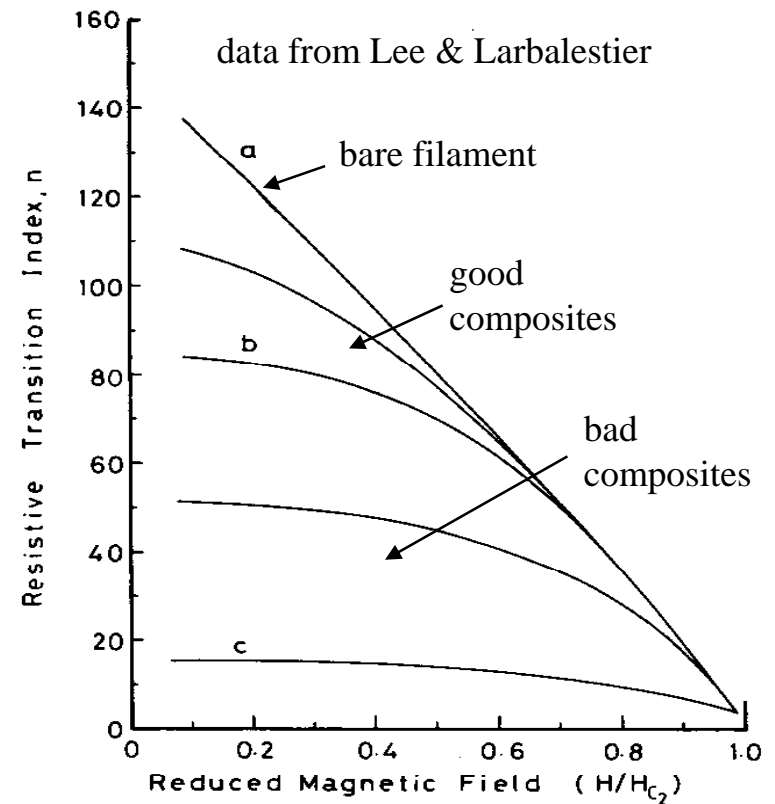
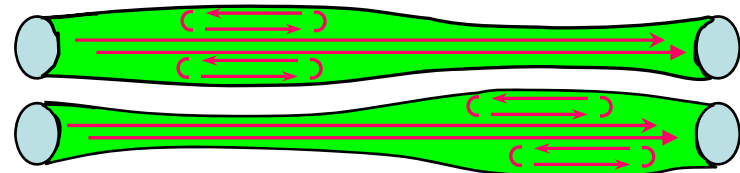


IGC SSC B944-2 (CuMn
around filaments) $r = 1.23$

wire 2A212 by European Advanced Superconductors

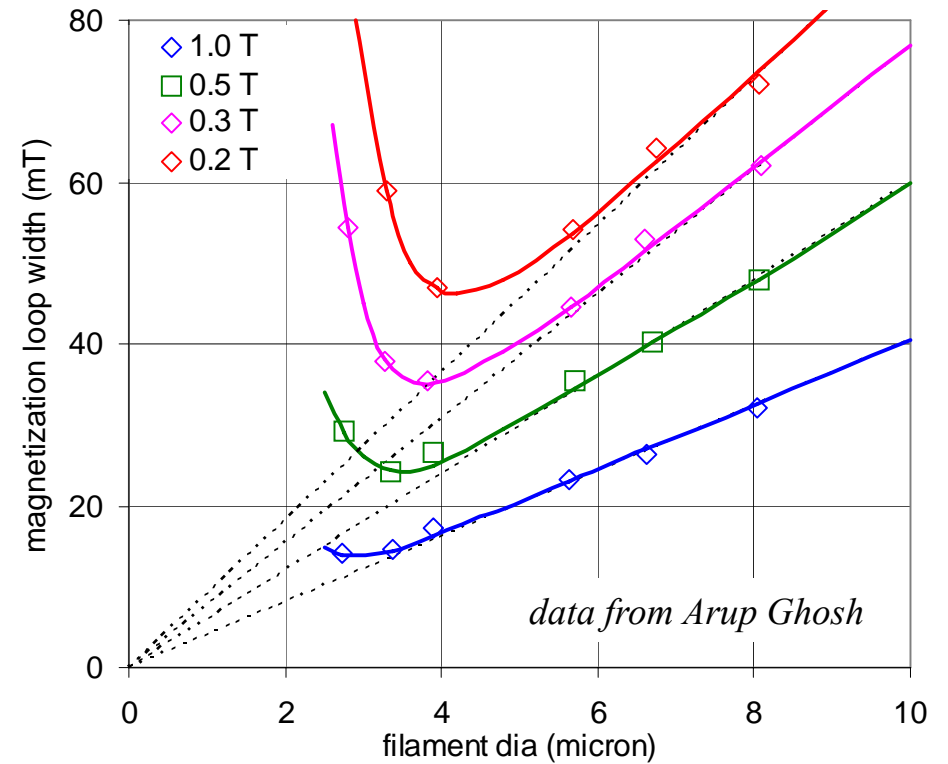
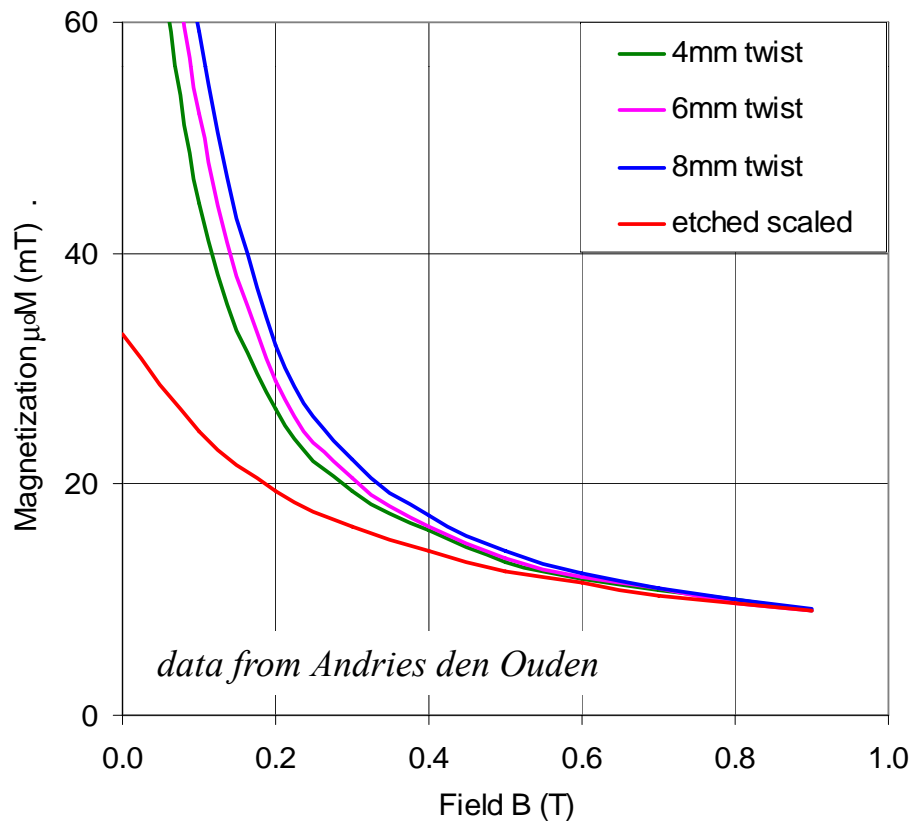
Fine filament distortion: why is $r < 1$?

- transport current determined by narrowest paths
- magnetization current fills up the rest
- so $r = \frac{J_{cmag}}{J_{ct}}$ should be > 1
- but J_{ct} is measured with a certain electric field - usually $10^{-14} \Omega m$
- J_{cmag} is measured with zero electric field
- even bare filaments have an ' n ' value
- estimate the decay of magnetization currents
- for $n = 100$ and a $6 \mu m$ filament, after 100 sec, J_{cmag} will have decayed to 88% of its $10^{-14} \Omega m$ value



Fine filaments: proximity coupling

- magnetization reduces with filament diameter down to a point - then it increases
- effect is strongest at low field



- expected linear decrease is restored when filaments are etched
- enhancement of magnetization is $\sim (\text{twist pitch})^{-1}$

Fine filaments: proximity coupling

- experimental data on etching suggests that the effect is caused by supercurrents crossing the matrix



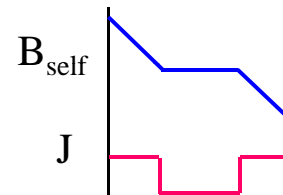
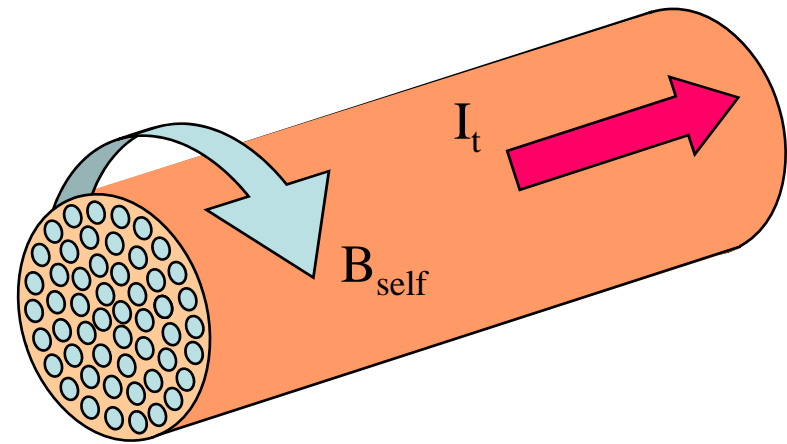
- linear dependence on twist pitch suggests these currents have a J_c
- Ghosh finds that transverse current density is given by $J_{\perp} = J_o e^{-ks}$ where s is the separation between the filaments and k depends on field and temperature
- for minimum sausaging and optimum wire yield, must have $s/d \sim 0.15$, where s is space between filaments and d is filament diameter - so $3\mu\text{m}$ filaments $\Rightarrow 0.45\mu\text{m}$ separation
- Collings finds that transverse currents are suppressed by ferromagnetic additions to the matrix metal - 0.5% Mn in copper works well
- adding Si to copper also suppresses proximity currents and also reduces CuTi formation during extrusion
- Sumption found that a wire made by (low temperature) hydrostatic extrusion without Nb diffusion barriers had no proximity coupling down to $2\mu\text{m}$ filament diameter - perhaps the Nb barriers help to launch Cooper pairs across the copper

Fine filaments: how many?

- self field, due to transport current penetrates from the outside of the wire
- J_c in outer filaments nothing inside
- twisting makes no difference
- penetration produces self field losses (per ramp)

$$Q_s = \frac{B_s^2}{2\mu_o} \left\{ \frac{4}{i} - 1 + 4 \frac{(2-i)}{i^2} \ln \left(\frac{2-i}{2} \right) \right\}$$

where $i = I_t / I_c$



- when the self field loss becomes comparable with the hysteresis loss within the filaments, there is little to be gained from further subdivision
- for example, a 0.8mm diameter wire with 10^5 filaments of $2\mu\text{m}$ diameter will have $Q_s / Q_h \sim 50\%$ when ramped from 1T to 6T with $i = 0.7$

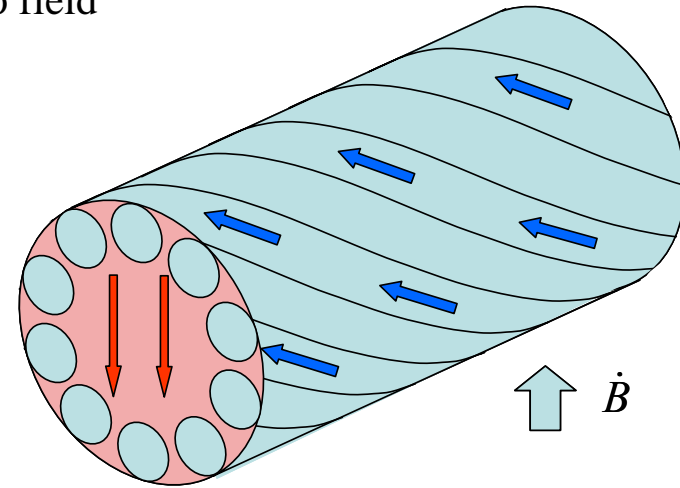
Eddy current coupling between filaments in wires

- currents flow along filament and across matrix parallel to field

- induced magnetization
$$M = \frac{2}{\mu_0} \dot{B} \tau$$

- current decay time
$$\tau = \frac{\mu_0}{2\rho_{et}} \left(\frac{p}{2\pi} \right)^2$$

- loss power
$$P = \frac{\dot{B}_i^2}{\mu_0} 2\tau = \frac{\dot{B}_i^2}{\rho_{et}} \left(\frac{p}{2\pi} \right)^2$$



where p = twist pitch and ρ_{et} is the effective transverse resistivity across the matrix

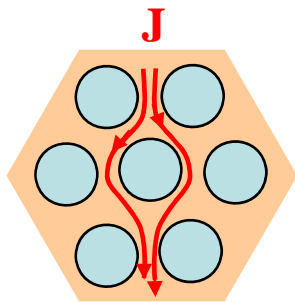
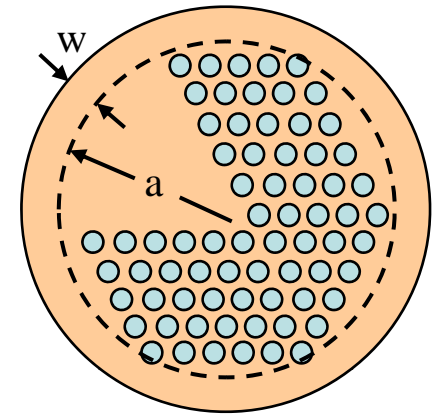
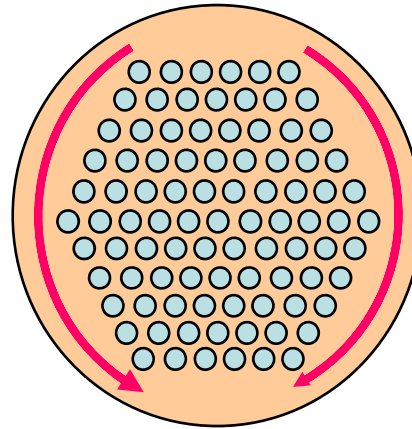
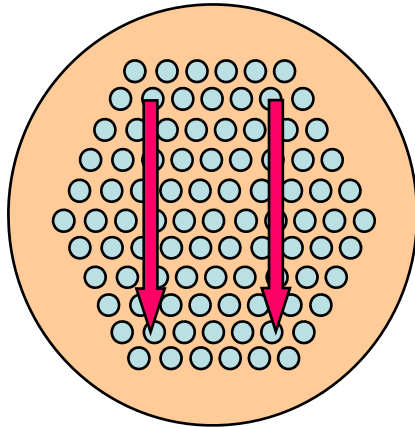
- general formulation in terms of multiple time constants*

$$P = \frac{2\dot{B}_i^2}{\mu_0} \sum_n \tau_1 + \tau_2 + \tau_3 \dots$$

*Duchateau, Turck and Ciazynski: Handbook on Applied Superconductivity B4.3

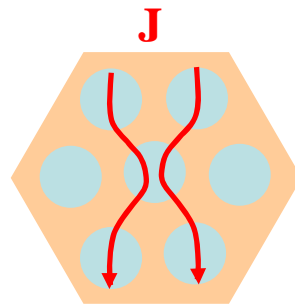
Effective transverse resistivity

Two main types of current path



poor contact

$$\rho_{tp} = \rho_m \frac{1 + \lambda}{1 - \lambda}$$



good contact

$$\rho_{tg} = \rho_m \frac{1 - \lambda}{1 + \lambda}$$

$$\frac{1}{\rho_{et}} \approx \frac{1}{\rho_t} + \frac{w}{a\rho_m} + \frac{aw}{\rho_m} \left(\frac{2\pi}{p} \right)^2$$

eddy currents

- add reciprocal resistances
- or add time constants
(Duchateau et al treatment is more exact)

Matrix resistance

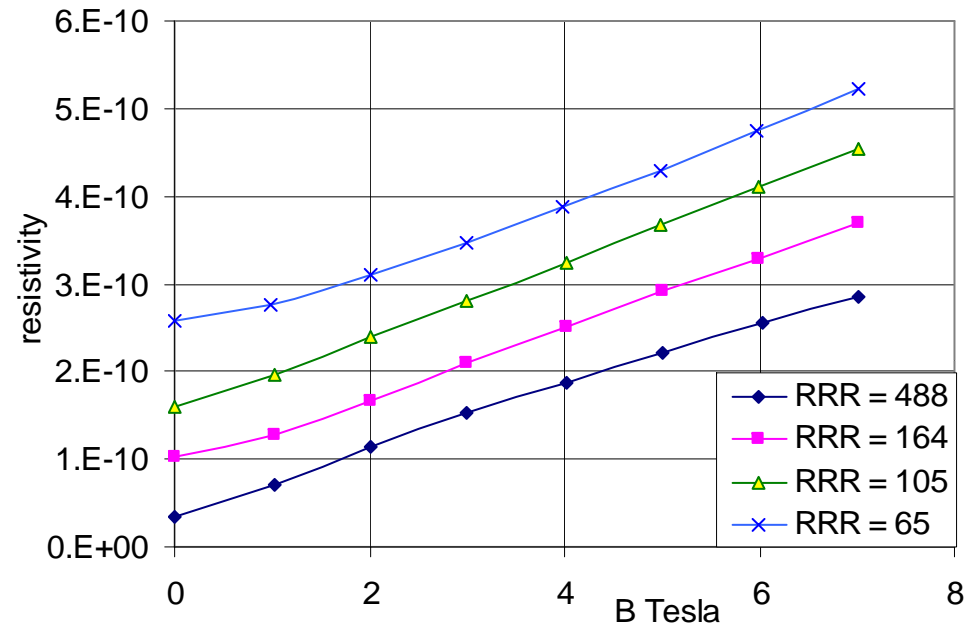
1) Magnetoresistance

- lots of good data from Fickett
- all for perpendicular B
- but it's all we have - fitted by

$$\rho(B) = (1 + r) \rho_{B=0}$$

$$\beta = \log \left\{ \frac{15.5 \times 10^{-9} B}{\rho_{B=0}} \right\}$$

$$\log(r) = -2.66 + 0.317 \beta + 0.623 \beta^2 - 0.184 \beta^3 + 0.0183 \beta^4$$



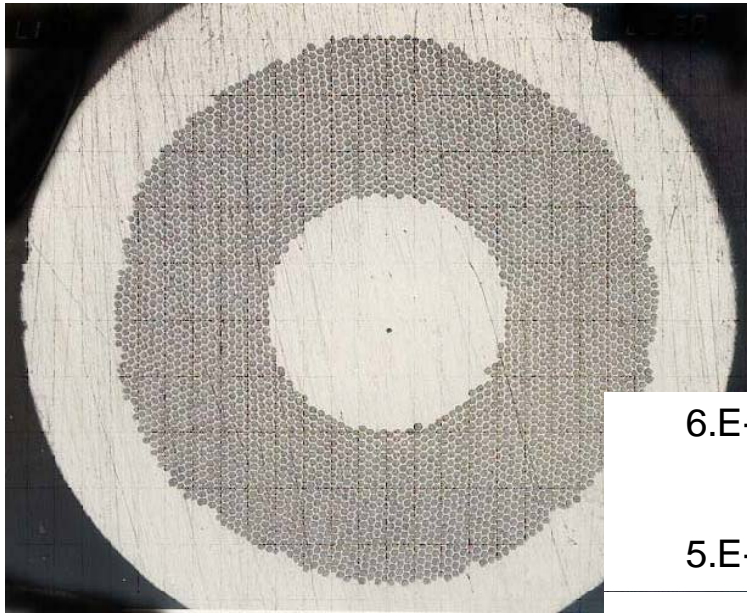
2) Size effect

- separation of filaments is comparable with electron mean free path \Rightarrow increase in resistivity to ρ_s

$$\rho_s = \rho_o(1 + l/s)$$

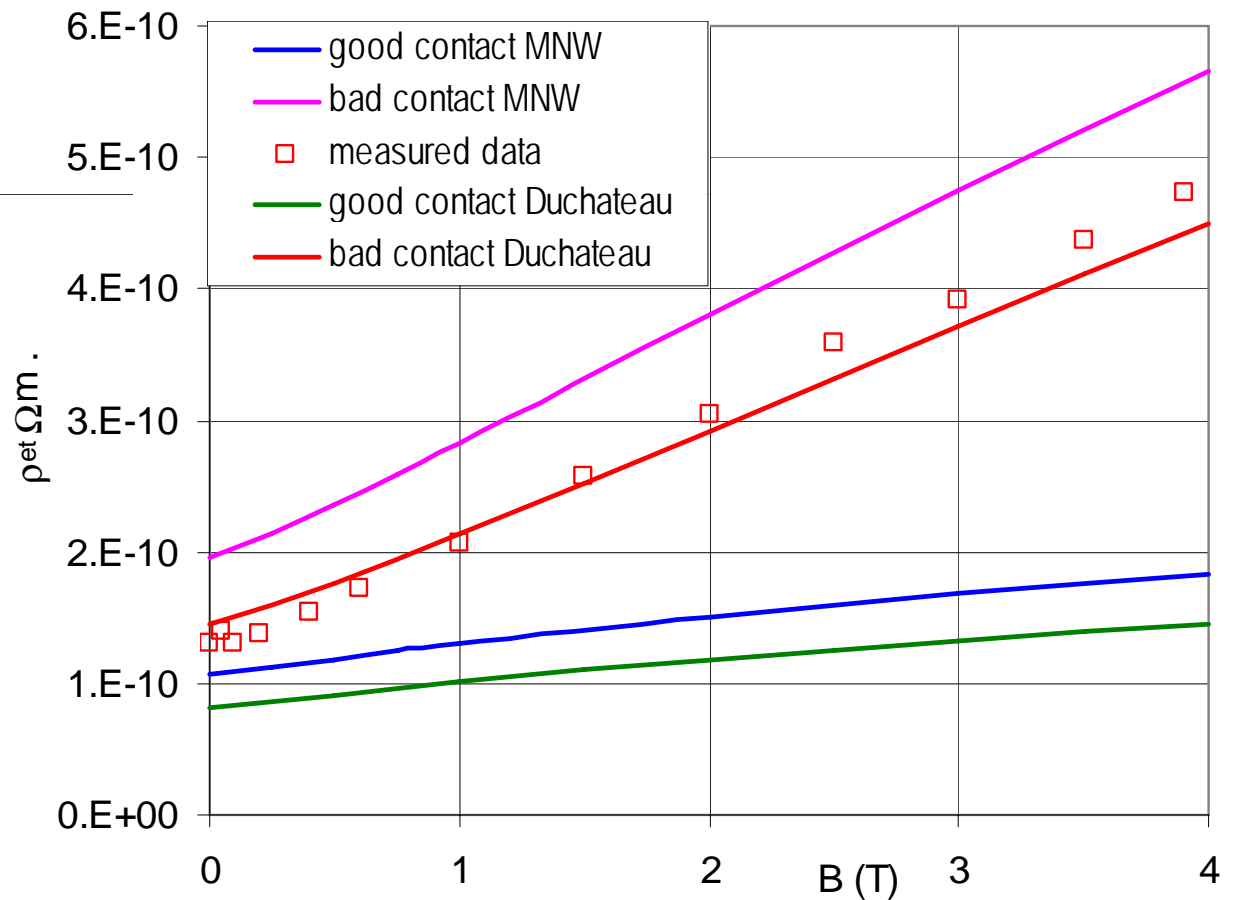
where l is the electro mean free path; for copper $\rho_o l = 6.45 \times 10^{-16} \Omega m^2$

- example: for RRR= 150 and an inter-filament spacing of $1\mu m$, the resistivity of copper between filaments is increased by a factor 6.7

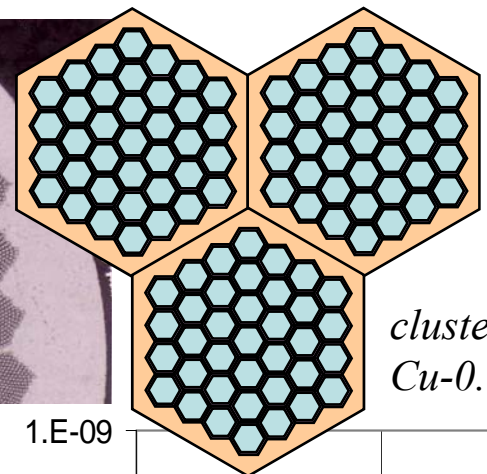
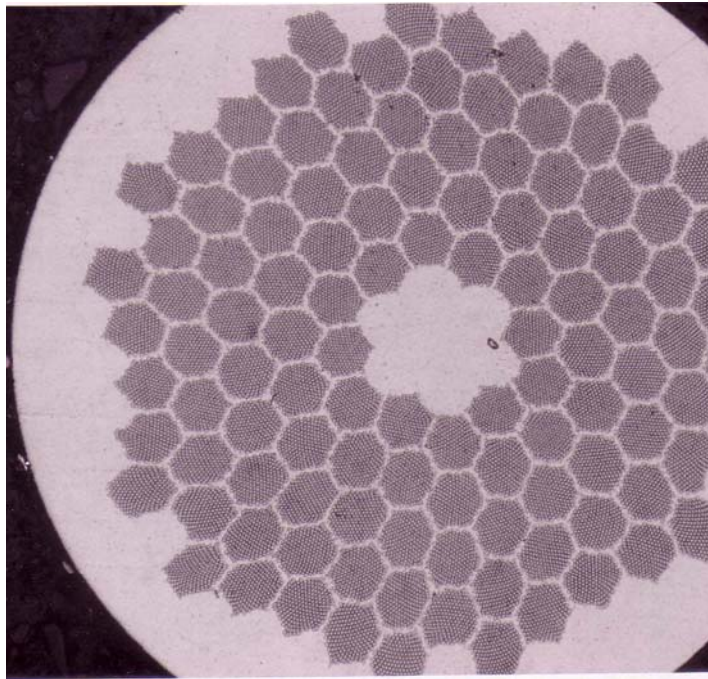


Calculated and measured ρ_{et}

- RHIC wire with 6 μ m filaments and 13mm twist pitch
- theory of Duchateau fits better because it includes the central island
- good or poor contact?
- *measure it!*

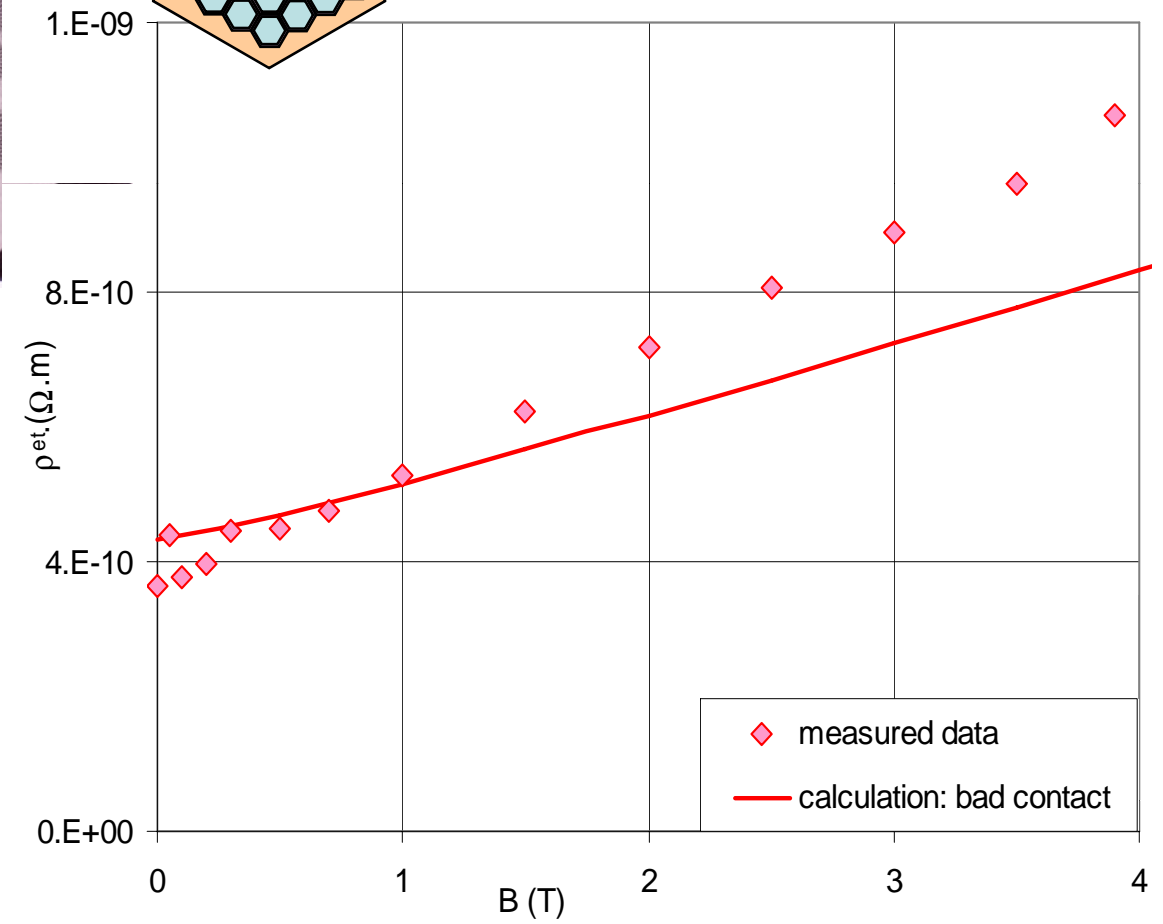


Another example



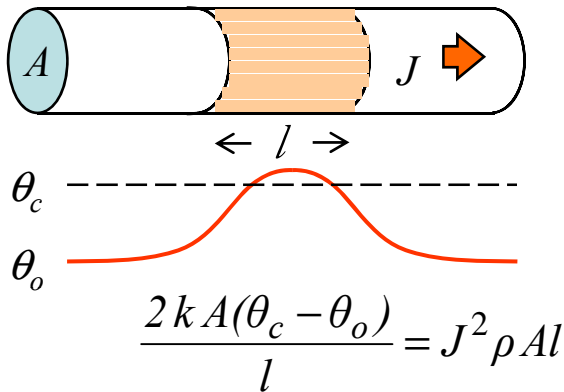
clusters of filaments surrounded by Cu-0.6wt%Mn, all in a sea of copper

- IGC B944-02-20: wire diameter 0.65mm, filament diameter 2.6 μ m
- model as 'macro-filaments, bad contact applies because there is no superconducting path across macro filaments
- ρ_{ef} increased by only a factor ~ 3 , although $\rho_{CuMn} = 250 \times 10^{-10} \Omega m \sim 60 \times$ the local copper



Constraints on increasing ρ_{et}

Crude model for MQE



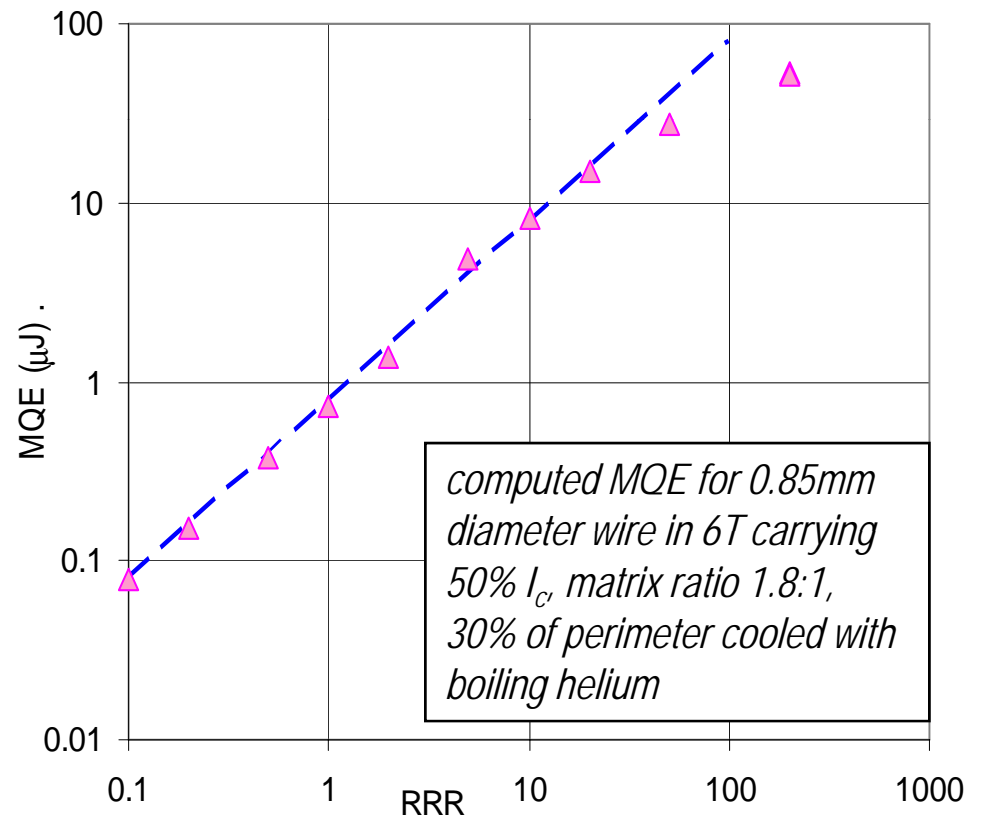
(all parameters averaged over the cross section)

$$l = \left\{ \frac{2k(\theta_c - \theta_o)}{J^2 \rho} \right\}^{\frac{1}{2}} \cong \frac{[L_o(\theta_c^2 - \theta_o^2)]^{\frac{1}{2}}}{J_c \rho}$$

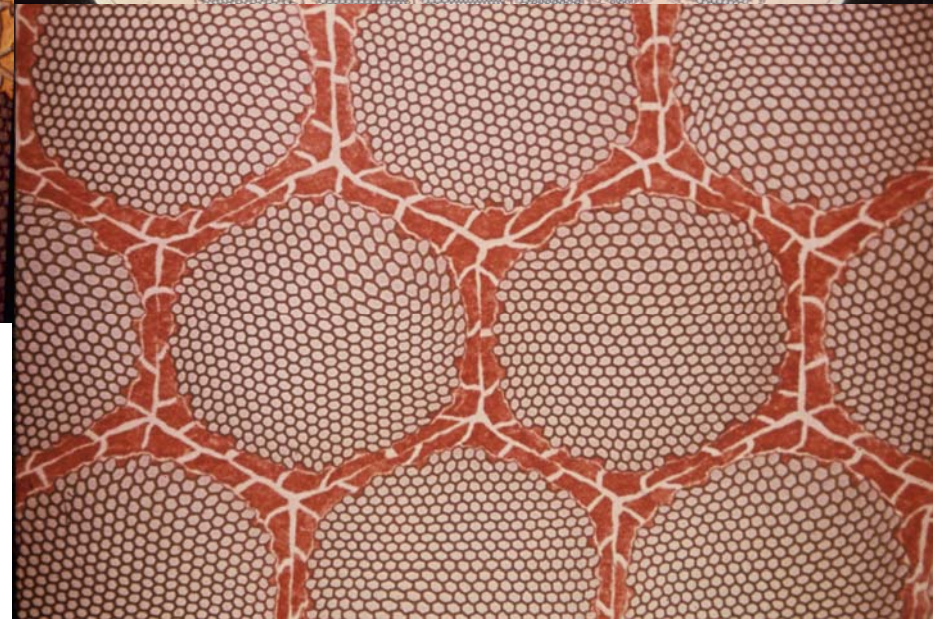
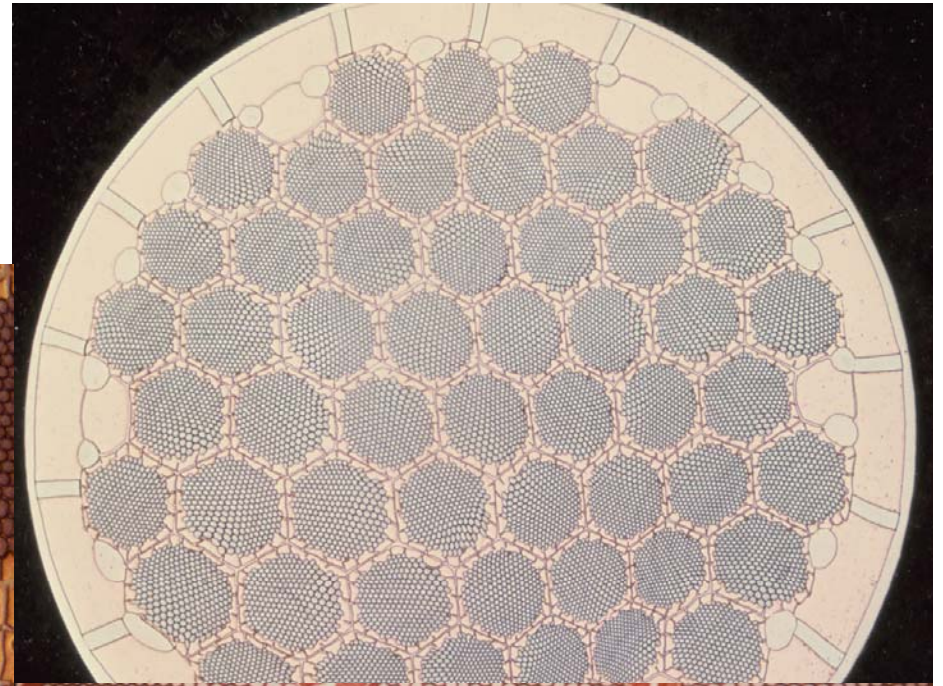
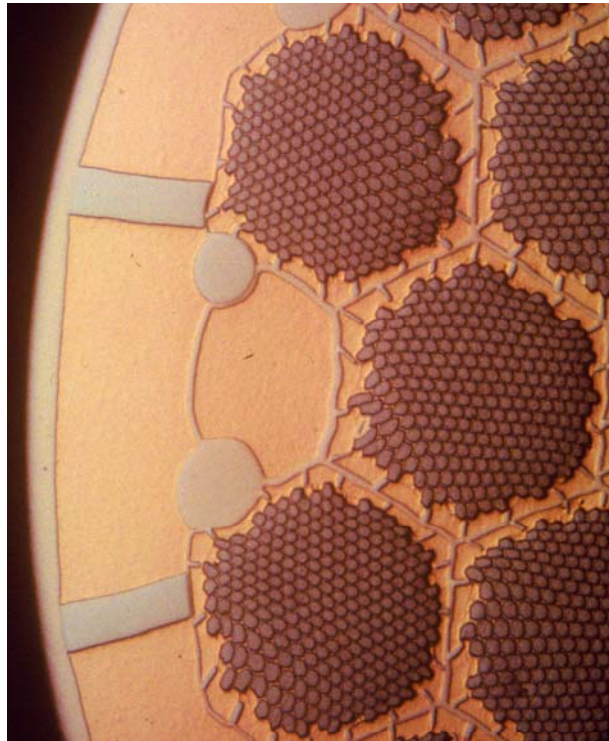
(using Wiedemann Franz Law $L_o =$ Lorentz number)

Conclude: need matrix with a resistivity which is low in longitudinal and high in transverse directions - anisotropic material

- use resistive alloy in the matrix
- but conflict with stability (early experiments on training)
- take minimum quench energy **MQE** as a criterion of stability



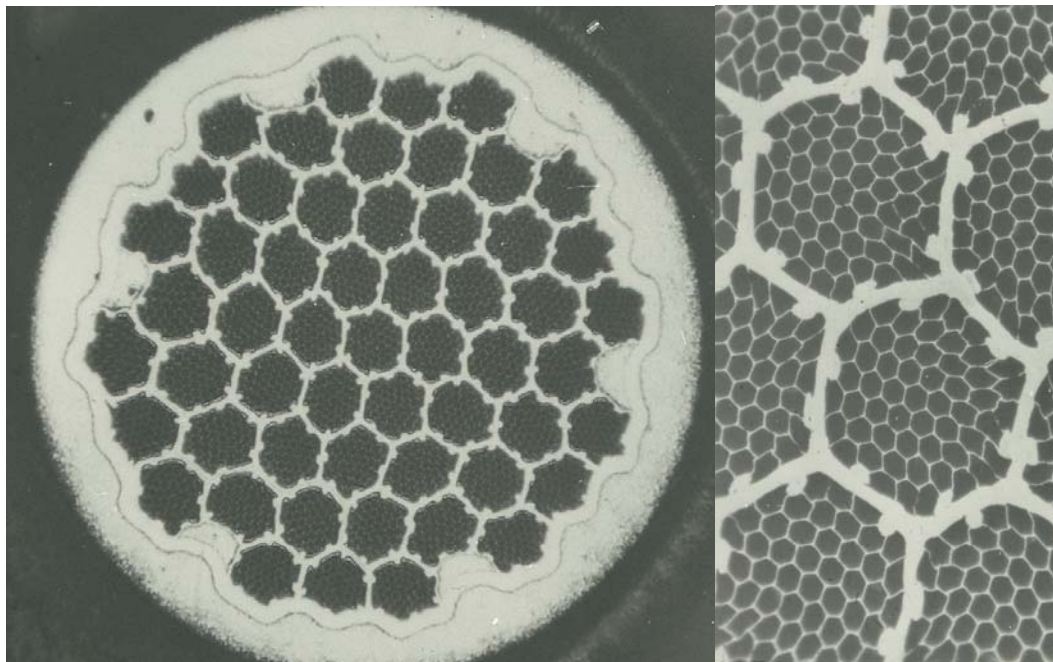
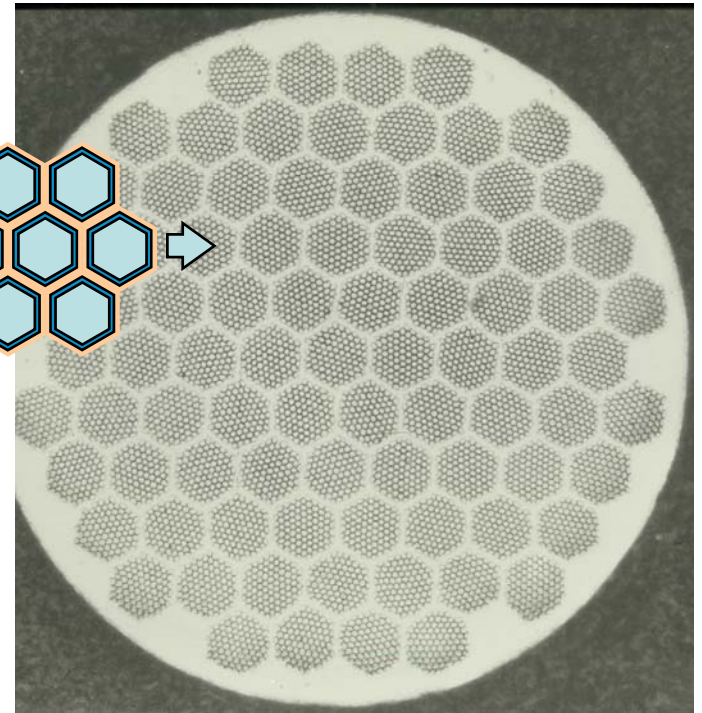
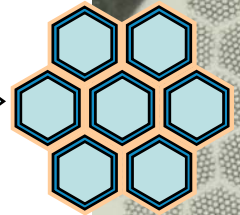
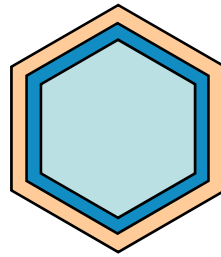
Anisotropic ρ : the physicist's idea



- good blocking of currents across filament clusters and around the jacket
- **problem:** they couldn't make it!

Anisotropic ρ : the wire maker's idea

- barrier round each filament, immerse in a sea of copper
- good mechanical properties for drawing
- **problem:** only change ρ_t from good to bad contact
- **problem:** conduction round the outer jacket



idea 2

- resistive material throughout the core
- thick barrier between core and jacket
- copper jacket
- low losses
- **problem:** stability - the copper is too far from the filaments

Stability: do filaments see the copper?

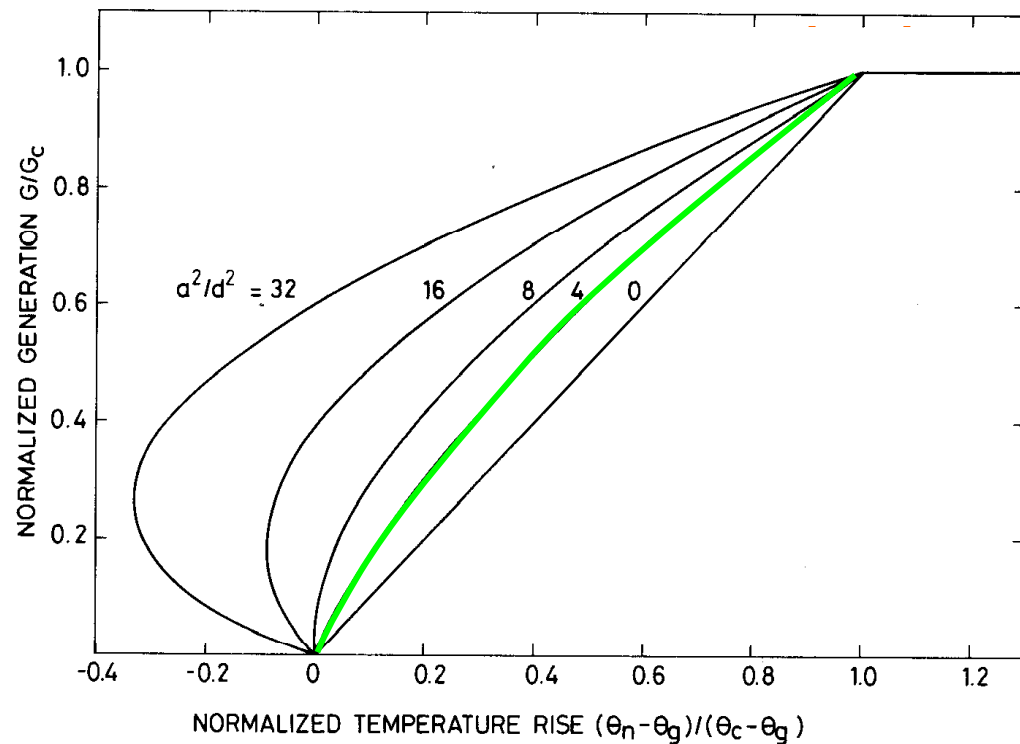
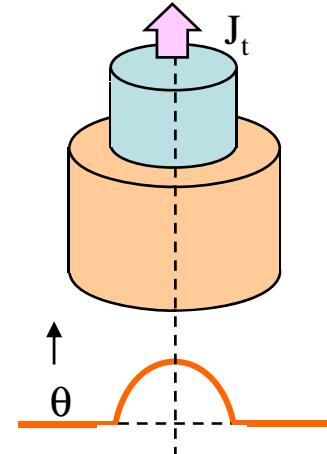
- MQE analysis assumes that the NbTi are intimately mixed - how intimate?
- over long lengths the electric field in NbTi and copper are the same
- what about the temperature?
 - uniform over Cu but not NbTi

- define a characteristic distance

where k = thermal conductivity of NbTi, θ_s = current sharing temperature, J_t = transport current density in NbTi, λ = local filling factor, ρ = copper resistivity, a = filament radius

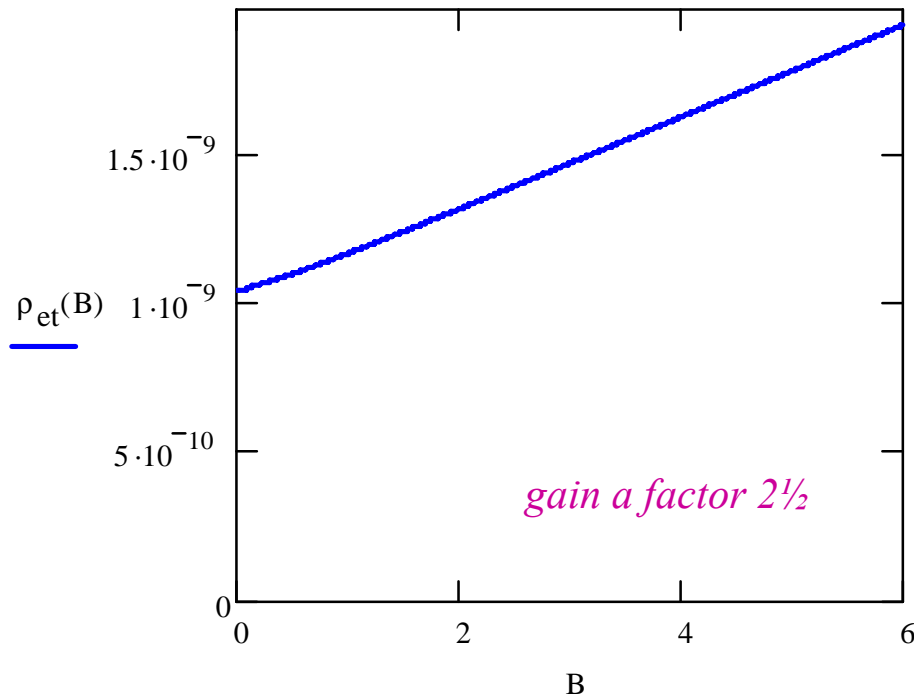
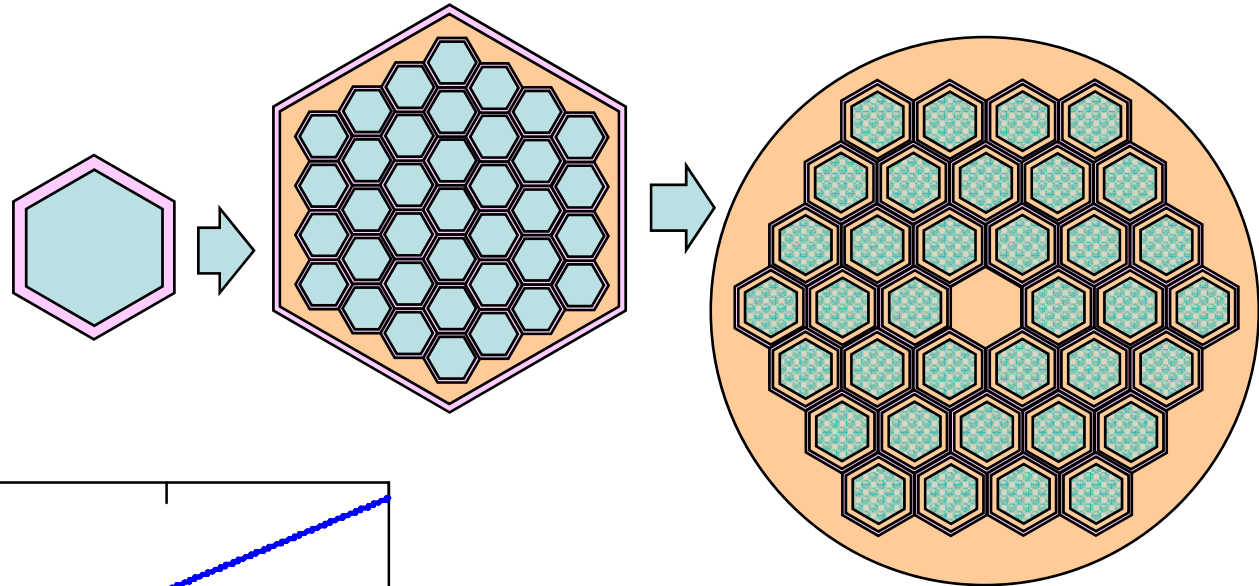
$$d^2 = \frac{k(\theta_c - \theta_s)(1 - \lambda)}{\lambda J_t^2 \rho}$$

- solve for power generation as a function of copper temperature θ_n
- for acceptable behaviour choose $a^2/d^2 < 4$, ie $d_{fil} < 4d$
- for NbTi in Cu at 6T $d \sim 10\mu\text{m}$
- so require $d_{fil} < 40\mu\text{m}$
- a mixture of NbTi and Cu typically has $k \sim 10 \times k_{\text{NbTi}}$
- so macro filament diameter can be $\sim 120\mu\text{m}$



Ideas for future wires (1)

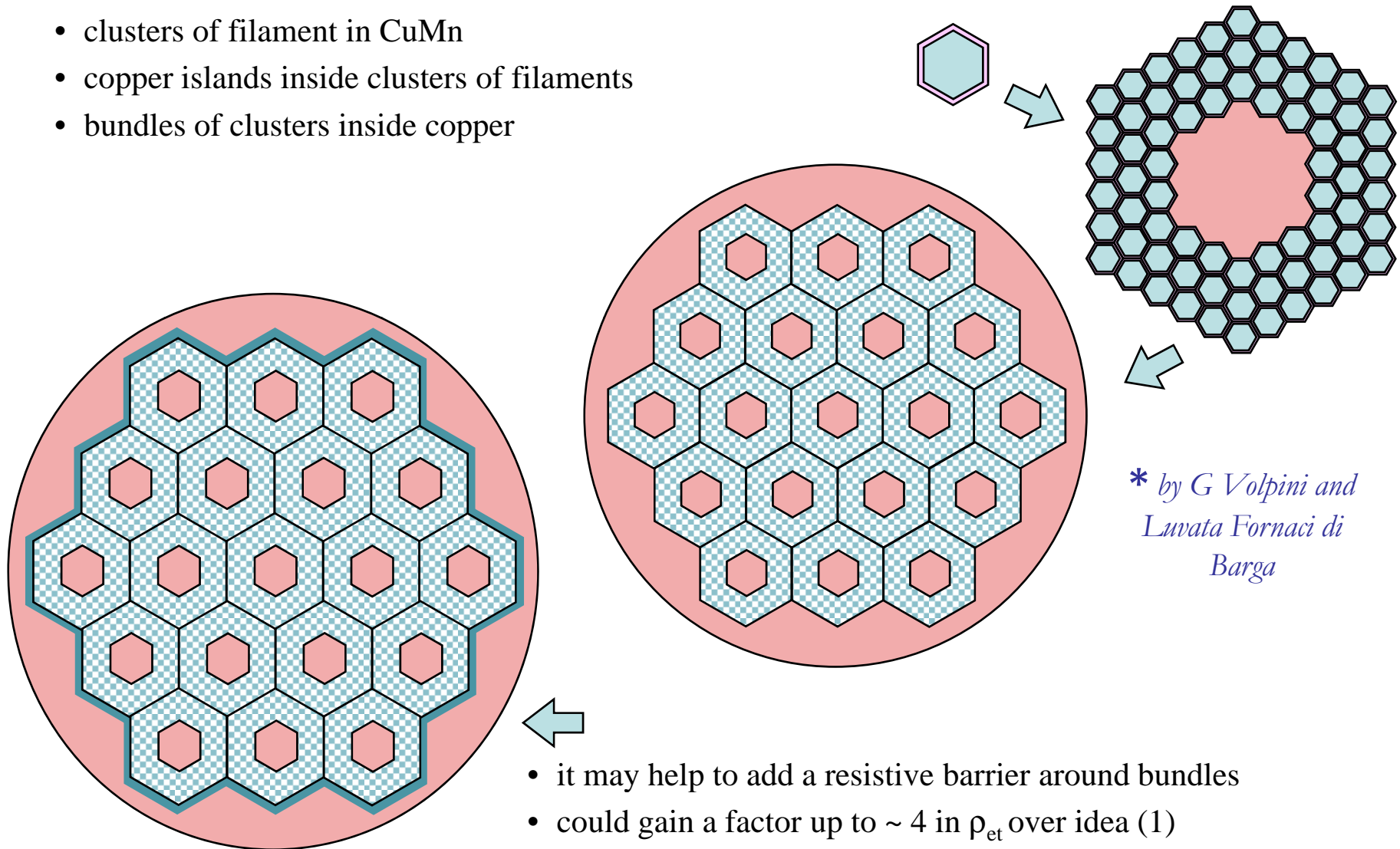
- barriers more efficient in blocking crossing current
- still respect the dynamic stability condition
- CuMn next to filament to suppress proximity coupling



resistivity across the core	$\rho_{ec}(0)$	$1.1 \times 10^{-8} \Omega m$
resistivity across the filamentary region	$\rho_{ef}(0)$	$2.6 \times 10^{-9} \Omega m$
around the outer barrier	$\rho_{eb}(0)$	$7.4 \times 10^{-8} \Omega m$
around the outer Cu jacket	$\rho_{eo}(0)$	$2.5 \times 10^{-9} \Omega m$
overall transverse resistivity for the wire	$\rho_{et}(0)$	$1.11 \times 10^{-9} \Omega m$

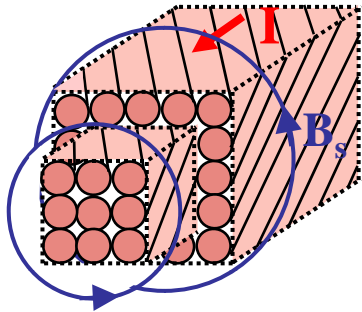
*Ideas for future wires (2) - a better idea**

- clusters of filament in CuMn
- copper islands inside clusters of filaments
- bundles of clusters inside copper

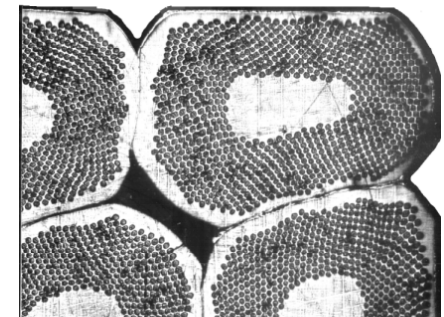
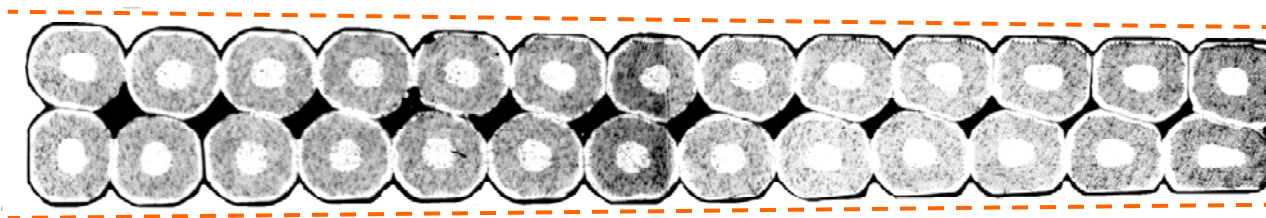
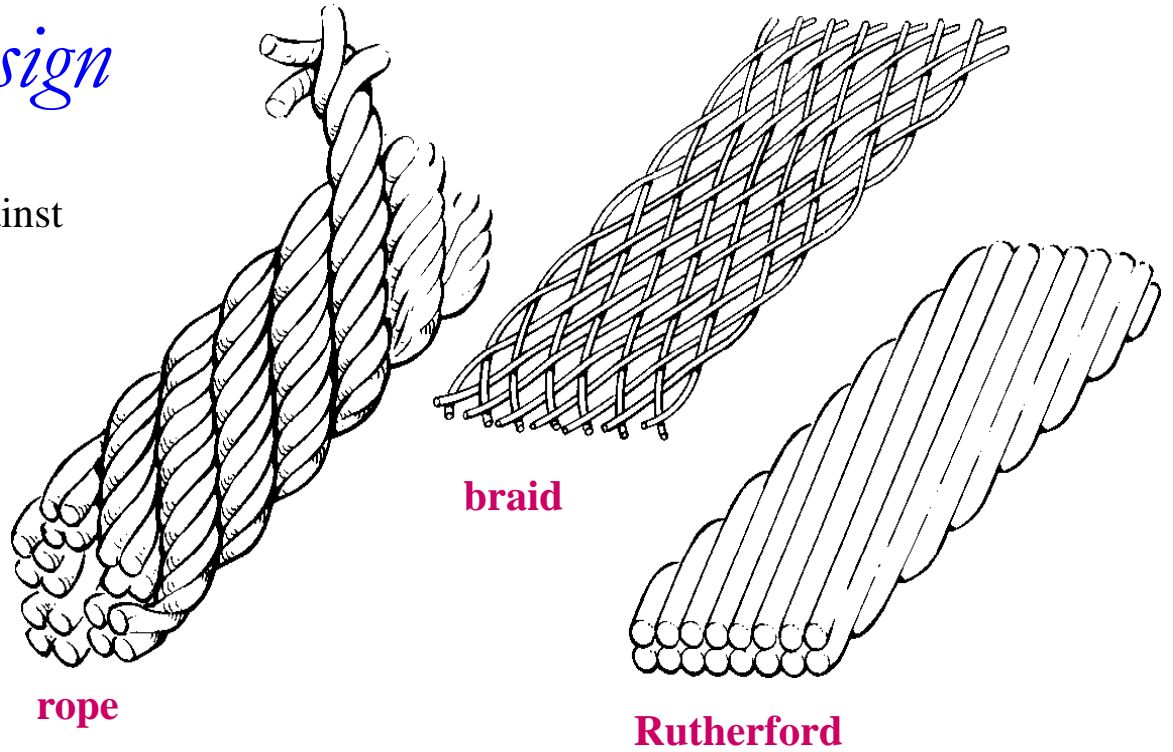


Cables: style of design

- wires must be fully transposed against self field

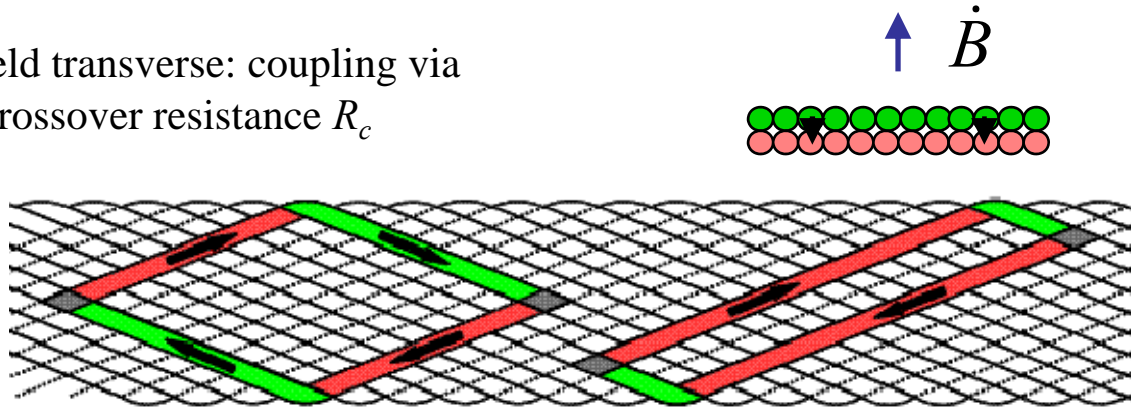


- rope: AC3
- braid: MOBY and early RHIC
- Rutherford: AC5 and Tevatron
- Rutherford probably won because it can be compacted to high density and tolerance



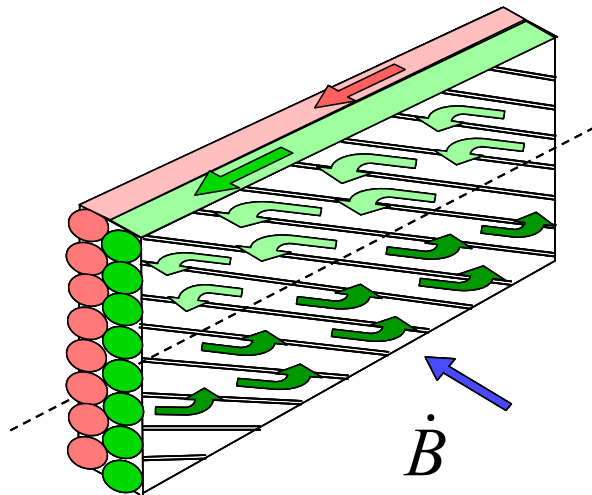
Cable coupling patterns

1) Field transverse: coupling via crossover resistance R_c

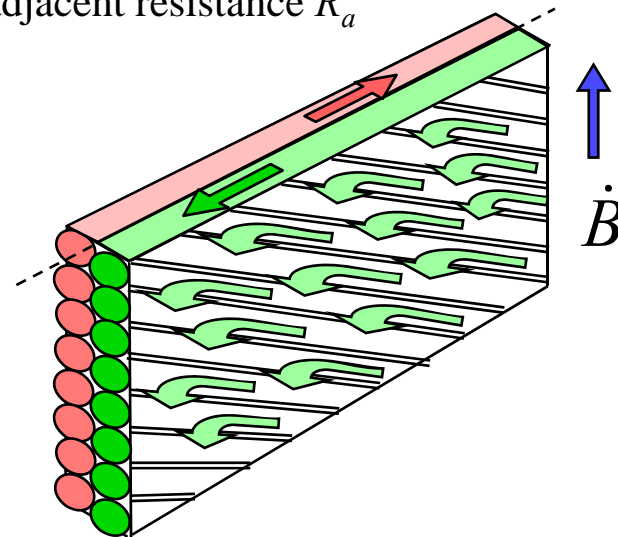


crossover resistance R_c
adjacent resistance R_a

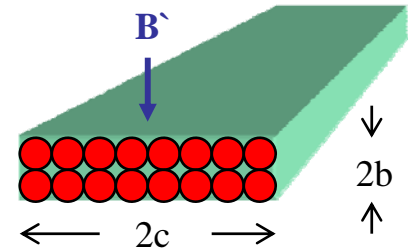
2) Field transverse: coupling via adjacent resistance R_a



3) Field parallel: coupling via adjacent resistance R_a



Coupling magnetization in cables



- Field transverse
coupling via crossover
resistance R_c

$$M_{tc} = \frac{1}{60} \frac{\dot{B}_t}{r_c} p^2 \frac{c^2}{b}$$

$$M_{tc} = \frac{1}{120} \frac{\dot{B}_t}{R_c} p \frac{c}{b} N(N-1)$$

where M = magnetization *per unit volume of cable*, p twist pitch, N = number of strands
 r_c and r_a are resistance * unit area of contact, R_c and R_a are resistance per contact

- Field transverse
coupling via adjacent resistance R_a

where θ = slope angle of wires $\cos\theta \sim 1$

$$M_{ta} = \frac{1}{12} \frac{\dot{B}_t}{r_a} p^2 \frac{c}{N \cos\theta}$$

$$M_{ta} = \frac{1}{6} \frac{\dot{B}_t}{R_a} p \frac{c}{b}$$

- Field parallel
coupling via adjacent
resistance R_a

$$M_{pa} = \frac{1}{16} \frac{\dot{B}_p}{r_a} p^2 \frac{b^2}{N c \cos\theta}$$

$$M_{pa} = \frac{1}{8} \frac{\dot{B}_p}{R_a} p \frac{b}{c}$$

(usually negligible)

- Field transverse
ratio crossover/adjacent

$$\frac{M_{tc}}{M_{ta}} = \frac{R_a}{R_c} \frac{N(N-1)}{20} \approx 45 \frac{R_a}{R_c}$$

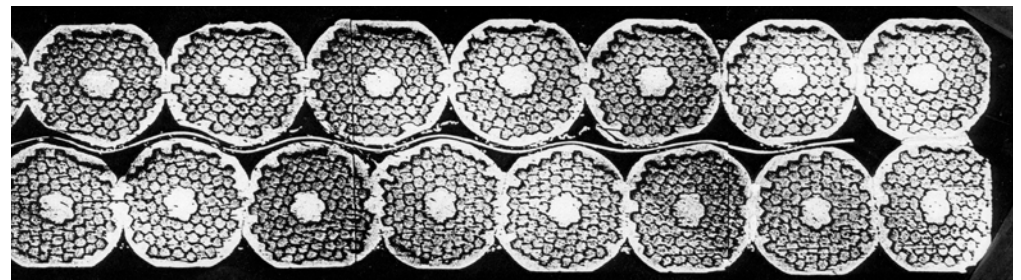
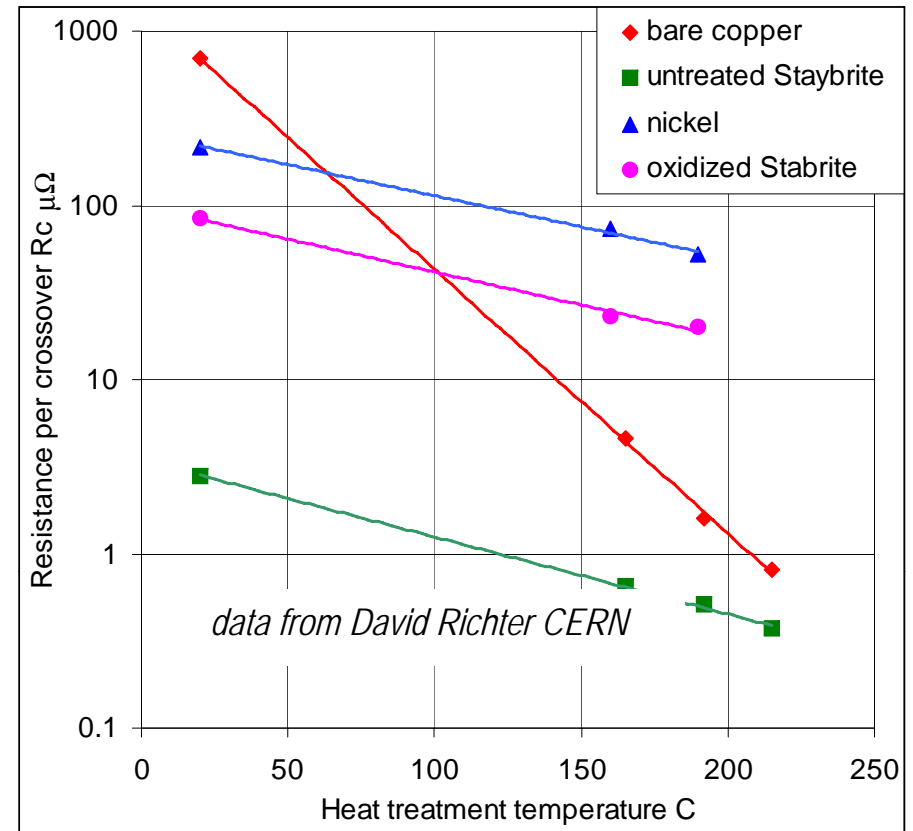
So without increasing loss too much can make R_a much less than R_c - anisotropy

R_a and R_c

- we can increase (and reduce losses) R_a and R_c by surface coatings and creative chemistry
- but do we want them to be too large?
- worries about stability and current sharing
- memories of MOBY and Rutherford quadrupole, type A/B behaviour in SSC booster dipoles
- suggest we should make R_a and R_c as large as necessary to limit the loss - but no larger
- because the loss is anisotropic, it pays to make R_a and R_c anisotropic

$$\frac{M_{tc}}{M_{ta}} = \frac{R_a}{R_c} \frac{N(N-1)}{20} \approx 45 \frac{R_a}{R_c}$$

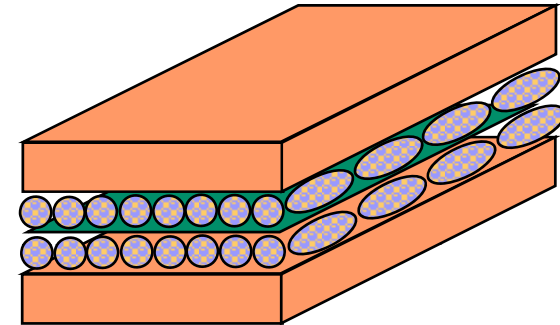
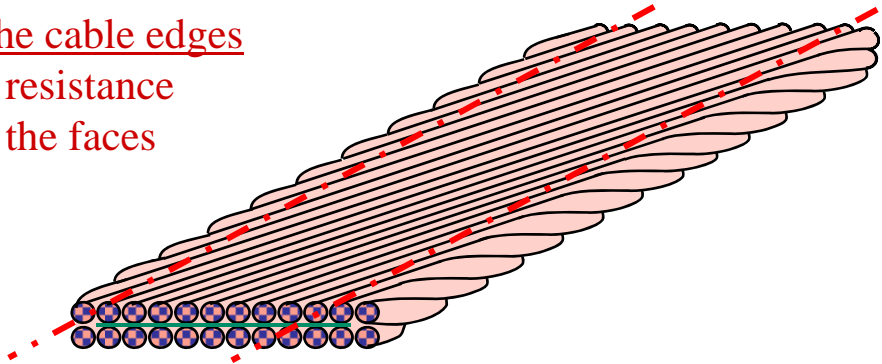
- cored cable, make $R_c \sim 40 \times R_a$
- lower losses with good stability



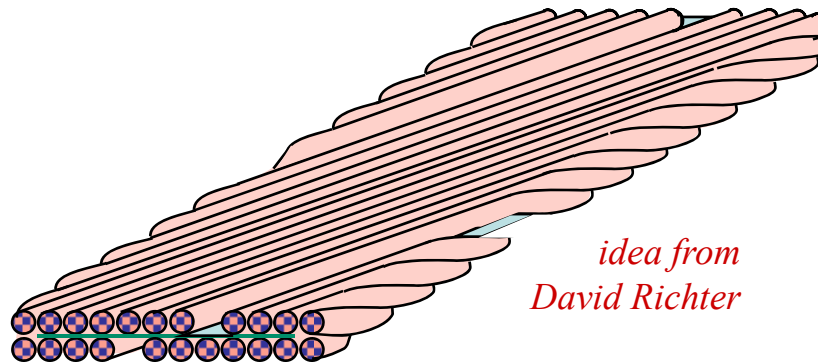
Measuring r_c when it's $\gg r_a$

Usually, only a tiny fraction of current goes through the core, making it difficult to measure r_c in an intact cable. Two methods of forcing current through the core:

- a) cut off the cable edges
measure resistance
between the faces



- b) remove two wires
measure
resistance
between the
remaining 2
groups of wires



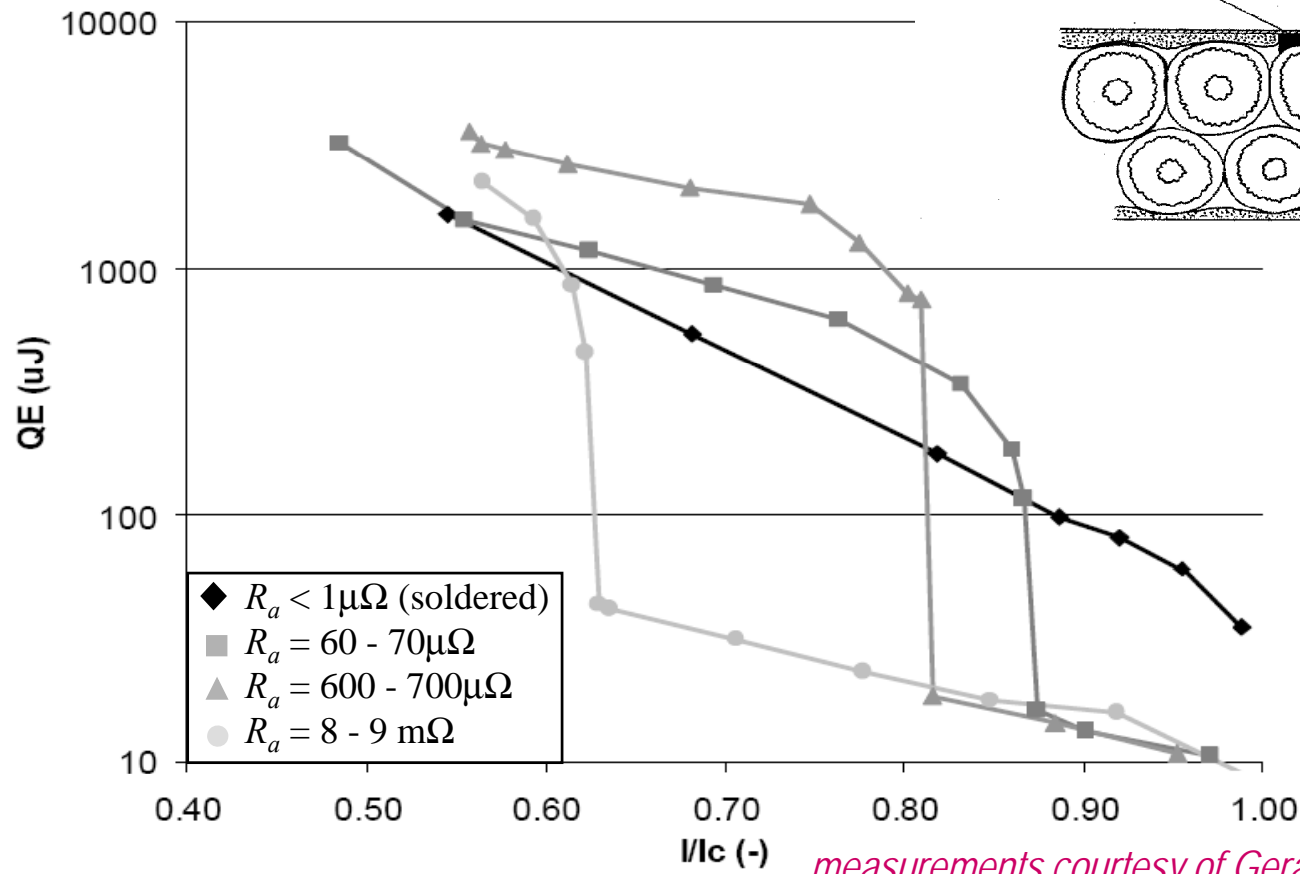
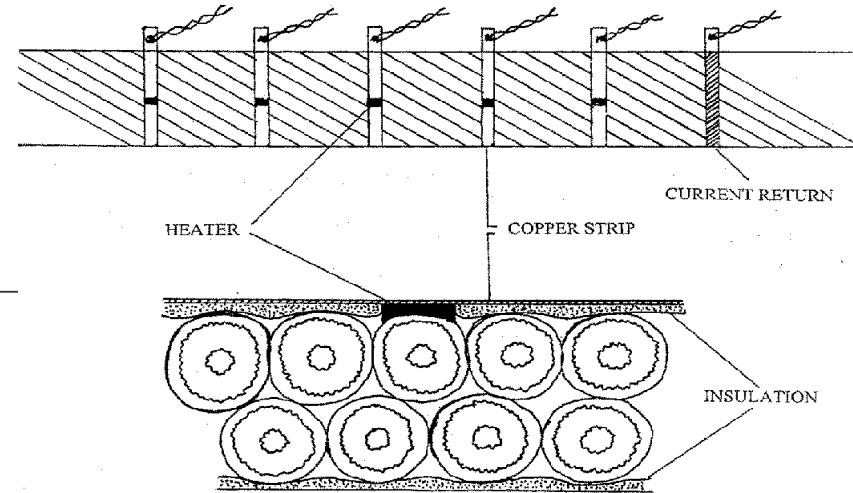
*idea from
David Richter*

Typical numbers

- for stainless core foil
find $R_c \sim 10\text{m}\Omega$
- for FAIR target $R_a \sim 200\mu\Omega$

Measuring cable stability

- use carbon paste heaters to inject short energy pulses to individual strands
- measure the MQE



measurements courtesy of Gerard Willering

- it looks like low R_a is best
- but how much does it really tell us about magnet stability?

Low loss NbTi Strand & Cable: concluding remarks

✧ Hysteresis Loss

- usually dominant \Rightarrow many very fine filaments (but not too many or self field loss)
- filament distortion: - longitudinal \Rightarrow low n - transverse \Rightarrow enhanced magnetization
- intermetallics: - diffusion barriers or low temperature extrusion
- stacking: - single stack \Rightarrow best properties - double stack \Rightarrow more filaments
- proximity coupling: - ferromagnetic additions to copper CuMn - or no diffusion barrier

✧ Coupling between filaments

- anisotropic matrix resistance - high transverse \Rightarrow low loss, - low longitudinal \Rightarrow stability
- MQE gives estimate of stability - critical distance for intimate mixing of NbTi and Cu
- new ideas needed for higher transverse resistance without losing stability

✧ Cables

- the high interface resistance needed to control losses high ramp rate may prejudice stability
 - surface coatings $\Rightarrow R_a > R_c$, - core $\Rightarrow R_a \ll R_c \Rightarrow$ low loss without losing stability

✧ NbTi

- now into middle age, NbTi still offers substantial advantages for pulsed use:
 - the finest filaments, low filament distortion,
 - precise fine structures of resistive alloy and copper in the matrix with no mixing
 - ductility